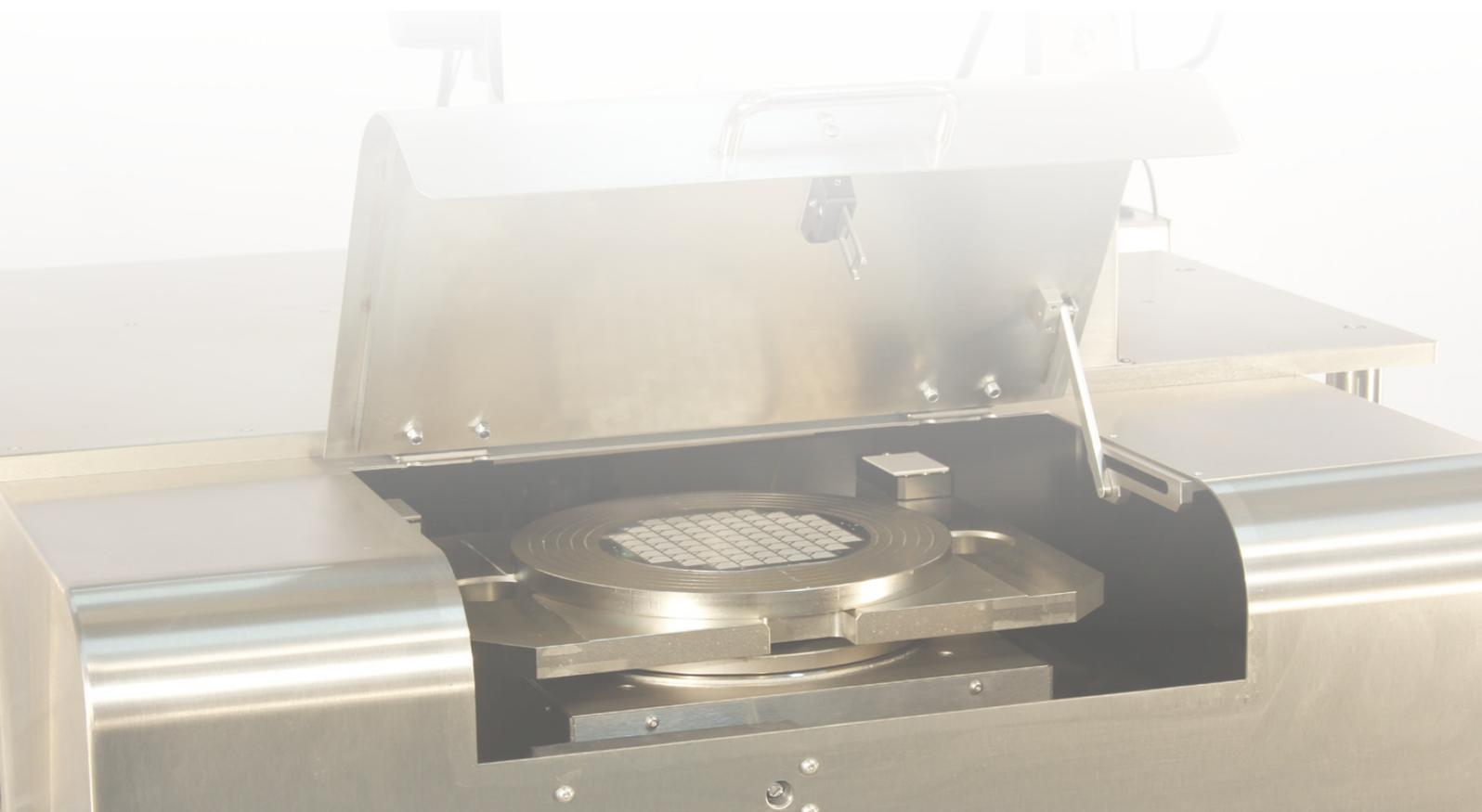


## PROBER ACCESSORIES

# ENVIRONMENTAL ENCLOSURES



# ENVIRONMENTAL CHAMBERS

The environment around your wafer prober can often affect your test results. We offer different enclosures to neutralise the environment – which could be natural or electrical – to ensure test results can be verified. In some cases the environment is required to protect the operator, as well as the test result.

Specifically designed to complement our semi-automatic and manual FA Series probers, both the ShieldMaster™ and GuardMaster™ environmental chambers are also compatible with some of our production wafer prober models. Thanks to their smart design, they enable easy access for optics, manipulators and probe cards.

When used with our semi-automatic FA series probe stations, the unique feature of an extended stage Y axis provides an uninhibited wafer loading position.



## SHIELDMASTER™ ENVIRONMENTAL ENCLOSURE

ShieldMaster™ provides a localized enclosure, ideal for frost-free low temperature probing. The compact ergonomic design encloses the stage area of the wafer prober.

It allows the chuck chamber to be quickly purged with dry air or nitrogen to remove any residual moisture and prevent condensation build-up and water freezing in the probe environment. This provides a stable environment for accurate probing at below ambient and subzero temperatures.

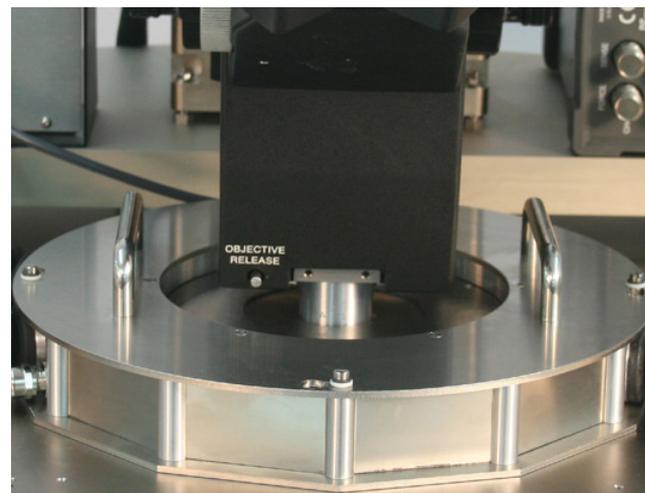
## GUARDMASTER™ EMC SHIELDED ENCLOSURE

GuardMaster™ provides a combined EMC shielded enclosure for low level measurements and frost-free low temperature probing.

Using the same compact design as ShieldMaster™, it features all the same benefits plus the ability to carry out sensitive measurements in an electrically shielded environment. It is therefore ideal for any applications requiring low leakage measurements.

## SAFETY INTERLOCKS

All enclosures can be provided with safety interlocks, breaking the electrical connections to prevent operators being exposed to hazardous environments like high voltages.



*GuardMaster™ for low signal*



*S200 with safety interlocks*

# DARK BOXES

Our dark boxes are designed to help you maintain the integrity of your test setup.

We provide enclosures suitable for use with any model of our manual and semi-automatic wafer probers. Furthermore, each is compatible with either our anti-vibration tables or work benches.

Both our standard and electrically shielded enclosures offer a smooth gliding action when opening or closing the doors from either left or right.

In addition, Wentworth dark boxes are designed with selectable side or rear cable entry. These features ease the test setup and enable convenient access to the chamber for quick adjustments prior to tests.

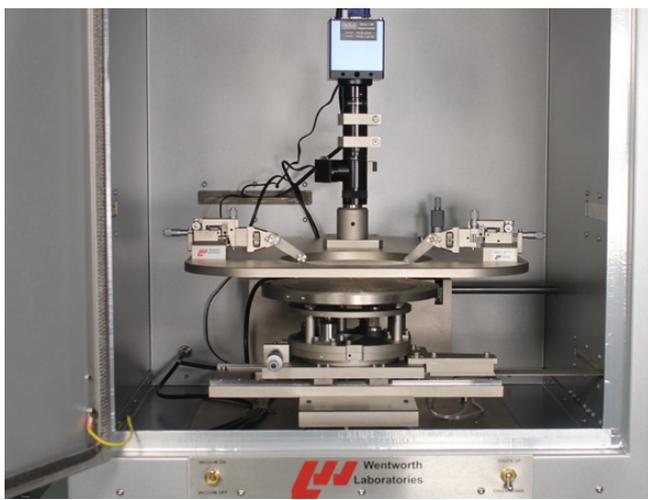
## STANDARD DARK BOXES

Our standard dark box creates a self-contained environment ideal for testing light-sensitive semiconductors requiring an enclosed, darkened environment.

A standard dark box is also recommended as a safety enclosure when conducting any laser work.



*Dark box with anti vibration table*



*Aspect L1 in EMC shielded dark box*

## ELECTRICALLY SHIELDED ENCLOSURES

In addition to the light shielding, in our EMC shielded dark box all edges are masked with special conductive foam, thereby electrically shielding the enclosure.

This ensures it is isolated so that test equipment is protected from external electromagnetic signals and reliable measurements can be taken for analytical applications.

An electrically shielded enclosure acts as a Faraday cage.

# ABOUT US

## A LEADING AUTHORITY IN FLEXIBLE PROBING SOLUTIONS SINCE 1967

Wentworth Laboratories is a leader in performance wafer probe stations and advanced cantilever probe cards. In close association with our customers, we play a pivotal role in the conception and development of cost-effective, productivity-enhancing wafer probing solutions for the semiconductor device test market. Our ability to craft customised and integrated wafer test solutions, with meticulous project communication and post-project monitoring, is second to none.

Our standard cantilever products accommodate blade and epoxy technology for a range of applications such as memory, RF and logic probe cards. Engineered solutions offer an impressive array of cantilever products for high voltage, extreme high and low temperatures and an unprecedented portfolio of bespoke products. We also offer design services for high speed, digital, analogue, mixed signal and memory applications.

Our global team supports probe card and wafer probing projects with sophisticated design, proven technology, experienced applications and technical support. Wentworth wafer prober products have been selected for many leading-edge wafer test applications across the semiconductor technology landscape, culminating in such products as hand-held devices, video game stations, PCs and medical diagnostic equipment, amongst others. As award-winning wafer test industry innovators, we are skilled in delivering wafer probers and cantilever probe card solutions that enable our customers to maximise their productivity and reduce cost.

The company was founded in 1967, has global representation and manufactures two major product lines. In our UK facilities, we manufacture wafer probers and cantilever probe cards whilst in the US, we manufacture cantilever probe cards and needle holder assemblies.



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